

MILITARY SPECIFICATION

MICROCIRCUITS, DIGITAL, ADVANCED LOW POWER
SCHOTTKY TTL, AND, OR, NAND, AND NOR GATES,
MONOLITHIC SILICON

This specification is approved for use by the Department of the Air Force, and is available for use by all Departments and Agencies of the Department of Defense.

1. SCOPE

1.1 Scope. This specification covers the detail requirements for monolithic silicon, ADVANCED, low-power Schottky TTL, positive AND, OR, -NAND, AND NOR logic gating microcircuits. Two product assurance classes and a choice of case outlines and lead finishes are provided and are reflected in the complete part number.

1.2 Part number. The part number shall be in accordance with MIL-M-38510, and as specified herein.

1.2.1 Device type. The device type shall be as follows:

<u>Device type</u>	<u>Circuit</u>
01	Quadruple 2-input NAND gate, buffer output
02	Quadruple 2-input NOR gate, buffer output
03	Quadruple 2-input NAND gate, open collector, buffer output
04	Quadruple 2-input AND gate, buffer output
05	Triple 3-input NAND gate, buffer output
06	Triple 3-input AND gate, buffer output
07	Dual 4-input NAND gate, buffer output
08	Quadruple 2-input OR gate, buffer output
09	Hex 1-input inverter gate, buffer output
10	Hex 1-input inverter gate, open collector, buffer output
11	Hex 1-input noninverting gate, buffer output
12	Hex 1-input noninverting gate, open collector, buffer output

1.2.2 Device class. The device class shall be the product assurance level as defined in MIL-M-38510.

1.2.3 Case outline. The case outline shall be designated as follows:

<u>Outline letter</u>	<u>Case outline (see MIL-M-38510, appendix C)</u>
A	F-1 (14-lead, 1/4" x 1/4", flat-pack)
B	F-3 (14-lead, 3/16" x 1/4", flat-pack)
C	D-1 (14-lead, 1/4" x 3/4", dual-in-line)
D	F-2 (14-lead, 1/4" x 3/8", flat-pack)
2	C-2 (20 terminal, .350" x .350", square chip carrier package)

1.3 Absolute maximum ratings.

Beneficial comments (recommendations, additions, deletions) and any pertinent data which may be of use in improving this document should be addressed to: Rome Air Development Center (RBE-2), Griffiss AFB, NY 13441, by using the self-addressed Standardization Document Improvement Proposal (DD Form 1426) appearing at the end of this document or by letter.

Maximum power dissipation (P_D) per device 1/	
Device type 01, 03-	35.2 mW dc
Device type 02, 04-	44 mW dc
Device type 05, 06-	33 mW dc
Device type 07-	17.6 mW dc
Device type 08-	55 mW dc
Device type 09, 10-	66 mW dc
Device type 11, 12-	77 mW dc
Lead temperature (soldering, 10 seconds)-	+300°C
Thermal resistance, junction-to-case (θ_{JC}):	
Cases A, B, D -	70°C/W
Case C -	50°C/W
Case 2 -	60°C/W
Junction temperature (T_J) -	+175°C

1.4 Recommended operating conditions.

Supply voltage- - - - -	4.5 V dc minimum to 5.5 V dc maximum
Minimum high-level input voltage (V_{IH})- -	2.0 V dc
Maximum low-level input voltage (V_{IL}) - -	0.8 V dc
Case operating temperature range (T_C) - -	-55°C to +125°C

2 APPLICABLE DOCUMENTS

2.1 Government specifications and standards. Unless otherwise specified, the following specifications and standards, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this specification to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of specifications, standards, handbooks, drawings, and publications required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting officer.)

2.2 Order of precedence. In the event of a conflict between the text of this specification and the references cited herein, the text of this specification shall take precedence.

3. REQUIREMENTS

3.1 Detail specification. The individual item requirements shall be in accordance with MIL-M-38510, and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Logic diagram and terminal connections. The logic diagram and terminal connections shall be as specified on figure 1.

3.2.2 Truth tables and logic equations. The truth tables and logic equations shall be as specified on figure 2.

3.2.3 Schematic circuits. The schematic circuits shall be submitted to the preparing activity prior to inclusion of a manufacturer's device in this specification and shall be submitted to the qualifying activity as a prerequisite for qualification. All manufacturers' schematics shall be maintained and available upon request.

I/ Must withstand the added P_D due to short circuit test (e.g., I_0).

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions $-55^{\circ}\text{C} \leq T_C \leq +125^{\circ}\text{C}$	Device type	Limits		Unit
				Min	Max	
High level output voltage	V_{OH}	$V_{CC} = 4.5 \text{ V}$ $I_{OH} = -1.0 \text{ mA}$	$V_{IH} = 2.0 \text{ V}$ $V_{IL} = 0.8 \text{ V}$	01,02,04 05,06,07 08,09,11	2.4 --	v dc
Low level output voltage	V_{OL}	$V_{CC} = 4.5 \text{ V}$ $I_{IN} = 12 \text{ mA}$	$V_{IL} = 0.8 \text{ V}$ $V_{IH} = 2.0 \text{ V}$	ALL	-- 0.4	v dc
Input clamp voltage	V_{IC}	$V_{CC} = 4.5 \text{ V}$ $I_{IN} = -18 \text{ mA}$	$T_C = +25^{\circ}\text{C}$	ALL	-- -1.5	v dc
Low level input current	I_{IL}	$V_{CC} = 5.5 \text{ V}$ $V_{IN} = 0.4 \text{ V}$	ALL	0	-100	μA
High level input current	I_{IH1}	$V_{CC} = 5.5 \text{ V}$ $V_{IN} = 2.7 \text{ V}$	ALL		20	μA
	I_{IH2}	$V_{CC} = 5.5 \text{ V}$ $V_{IN} = 7.0 \text{ V}$	ALL		100	μA
Output current 1/	I_O	$V_{CC} = 5.5 \text{ V}$ $V_O = 2.25 \text{ V}$	01,02,04, 05,06,07, 08 09,11	-15 -30	-112	mA
Collector cut-off current	I_{CEX}	$V_{CC} = 4.5 \text{ V}$ $V_{IN} = 5.0 \text{ V}$ $V_O = 5.5 \text{ V}$	03,10, 12		100	μA
Supply current, outputs high	I_{CCH}	$V_{CC} = 5.5 \text{ V}$	01,03 02 04,09,10 05 06 07 11,12	1.6 2.8 3 1.2 2.3 0.8 6		mA

See footnote at end of table.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions $-55^{\circ}\text{C} \leq T_{\text{C}} \leq +125^{\circ}\text{C}$	Device type	Limits		Unit
				Min	Max	
Supply current, outputs low	I_{CCCL}	$V_{\text{CC}} = 5.5 \text{ V}$		01,03	17.8	
				02	9.0	
				04,	9.3	
				05	6.0	
				06	7.0	
				07	3.9	mA
				08	10.6	
				09,10	12.0	
				11,12	14.0	
Propagation delay time low-to-high level	t_{PLH}	$V_{\text{CC}} = 5.0 \text{ V}$ $C_{\text{L}} = 50 \text{ pF} \pm 10\%$	$R_{\text{L}} = 500 \Omega$	01,02,05 07,11 04	2 2 2	1C II ns
				08	2	9
				06	2	12
				09	1	9
			$R_{\text{L}} = 680 \Omega$	03 10,12	10 5	40 35
Propagation delay time high-to-low level	t_{PHL}	$V_{\text{CC}} = 5.0 \text{ V}$ $C_{\text{L}} = 50 \text{ pF} \pm 10\%$	$R_{\text{L}} = 500 \Omega$	01,02,05 07	2	7
				04,06	3	II
				08	3	12
				09	1	8
				11	1	10
			$R_{\text{L}} = 680 \Omega$	03 10 12	2 2 2	12 12 14

1/ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS} .

3.2.4 Case outlines. The case outlines shall be as specified in 1.2.3.

3.3 Lead material and finish. The lead material and finish shall be in accordance with MIL-M-38510 (see 6.5).

3.4 Electrical performance characteristics. The electrical performance characteristics are as specified in table I, and apply over the full recommended case operating temperature range, unless otherwise specified.

3.5 Electrical test requirements. The electrical test requirements for each device class shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table III.

3.6 Marking. Marking shall be in accordance with MIL-M-38510. At the option of the manufacturer, marking of the country of origin may be omitted from the body of the microcircuit, but shall be retained on the initial container.

3.7 Microcircuit group assignment. The devices covered by this specification shall be in microcircuit group number 9 (see MIL-M-38510, appendix E).

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (see table III)	
	Class S devices	Class B devices
Interim electrical parameters (pre burn-in) (method 5004)	1	1
Final electrical test parameters (method 5004)	1*,2,3, 9,10,11	1*2,3, 9
Group A test requirements (method 5005)	1,2,3, 9,10,11	1,2,3, 9
Group B test requirements (method 5005) subgroup 5	1,2,3, 9,10,11	N/A
Group C end-point electrical parameters (method 5005)	N/A	1,2,3
Additional electrical subgroups for group C periodic inspections	N/A	10,11
Group D end-point electrical parameters (method 5005)	1,2,3	1,2,3

*PDA applies to subgroup 1 (see 4.2c).

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-M-38510 and methods 5005 and 5007, as applicable, of MIL-STD-883, except as modified herein.

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to qualification and quality conformance inspection. The following additional criteria shall apply:

4.3 Qualification inspection. Qualification inspection shall be in accordance with MIL-M-38510. Inspections to be performed shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, and D inspections (see 4.4.1 through 4.4.4).

a. Burn-in (method 1015 of MIL-STD-883).

(1) Test condition D or E, using the circuit shown on figure 3, or equivalent.

(2) $T_A = +125^\circ\text{C}$ minimum.

b. Interim and final electrical test parameters shall be as specified in table II, except interim electrical parameters test prior to burn-in is optional at the discretion of the manufacturer.

c. The percent defective allowable (PDA) shall be as specified in MIL-M-38510.

4.4 Quality conformance inspection. Quality conformance inspection shall be in accordance with MIL-M-38510. Inspections to be performed shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, and D inspections (see 4.4.1 through 4.4.4).

4.4.1 Group A inspection. Group A inspection shall be in accordance with table I of method 5005 of MIL-STD-883 and as follows:

a. Electrical test requirements shall be as specified in table II herein.

b. Subgroups 4, 5, 6, 7, and 8 of table I of method 5005 of MIL-STD-883 shall be omitted.

4.4.2 Group B inspection. Group B inspection shall be in accordance with table II of method 5005 of MIL-STD-883. Electrical test requirements shall be as specified in table II herein.

4.4.3 Group C inspection. Group C inspection shall be in accordance with table III of method 5005 of MIL-STD-883 and as follows:

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test (method 1005 of MIL-STD-883) conditions:

(1) Test condition D or E, using the circuit shown on figure 3, or equivalent.

(2) $T_A = +125^\circ\text{C}$ minimum.

(3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510.

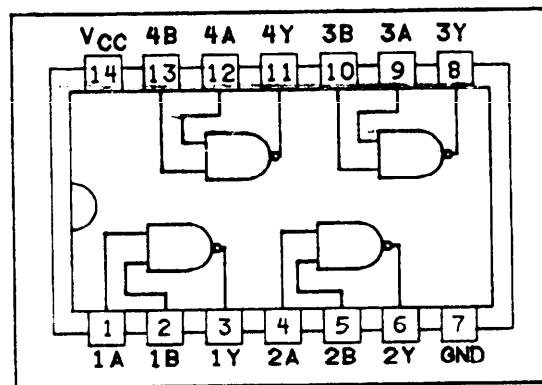
c. Subgroups 3 and 4 shall be added to group C inspection for class B devices and shall consist of the tests, conditions, and limits specified for subgroups 10 and 11 of group A.

4.4.4 Group D inspection. Group D inspection shall be in accordance with table IV of method 5005 of MIL-STD-883. End-point electrical parameters shall be as specified in table II herein.

4.5 Methods of inspection. Methods of inspection shall be specified as follows:

4.5.1 Voltage and current. All voltages given are referenced to the microcircuit ground terminal. Currents given are conventional and positive when flowing into the referenced terminal.

Device type 01 and 03
Cases A, B, C, and D



Device type 01 and 03
Case 2

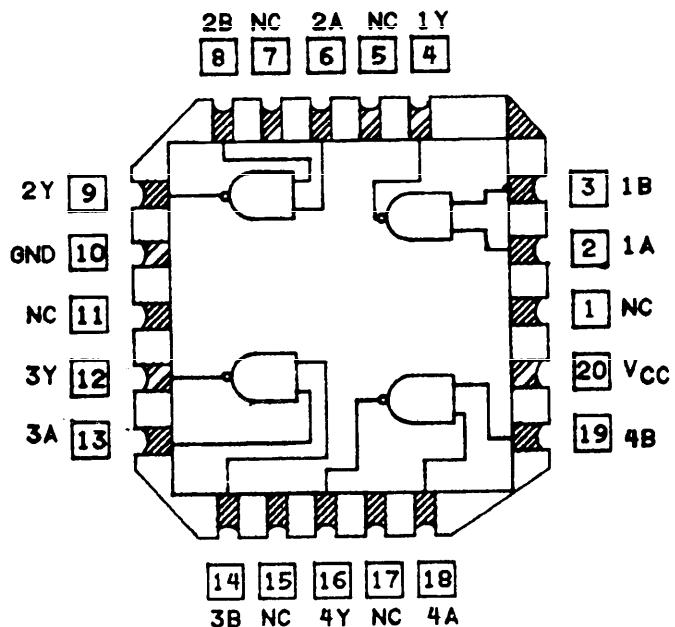


FIGURE 1. Logic diagram and terminal connections (top view).

Device type 02
Cases A, B, C, and D

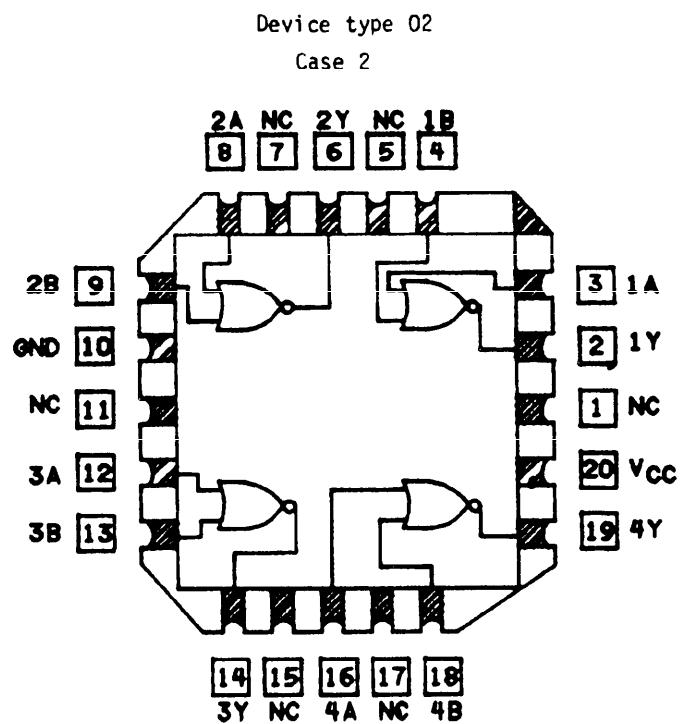
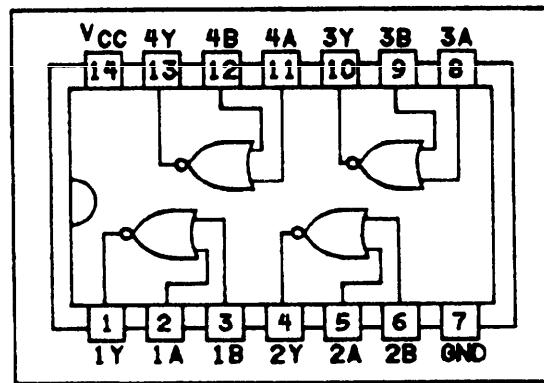


FIGURE 1. Logic diagram and terminal connections (top view).

Device type 04
Cases A, B, C, and D

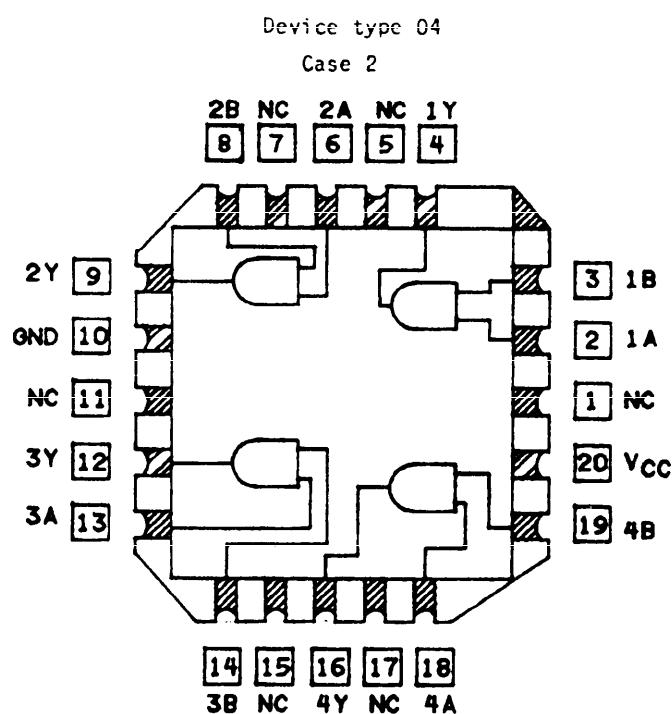
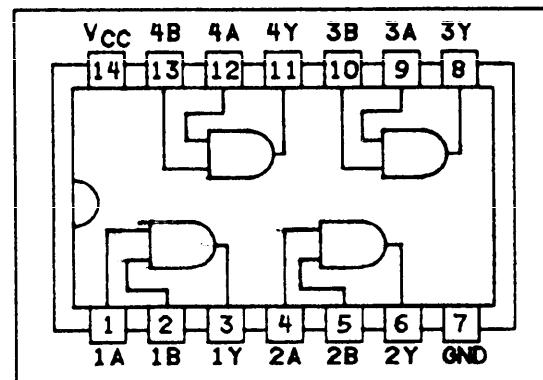
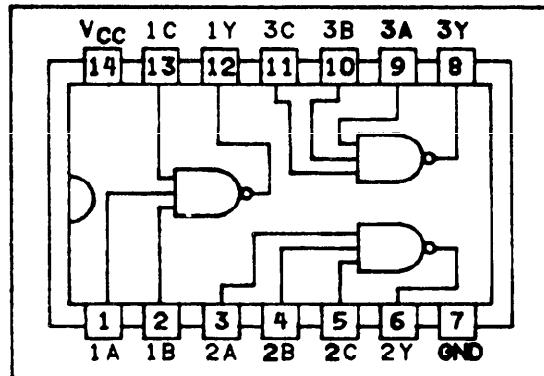


FIGURE 1. Logic diagram and terminal connections (top view).

Device type 05
Cases A, B, C, and D



Device type 05
Case 2

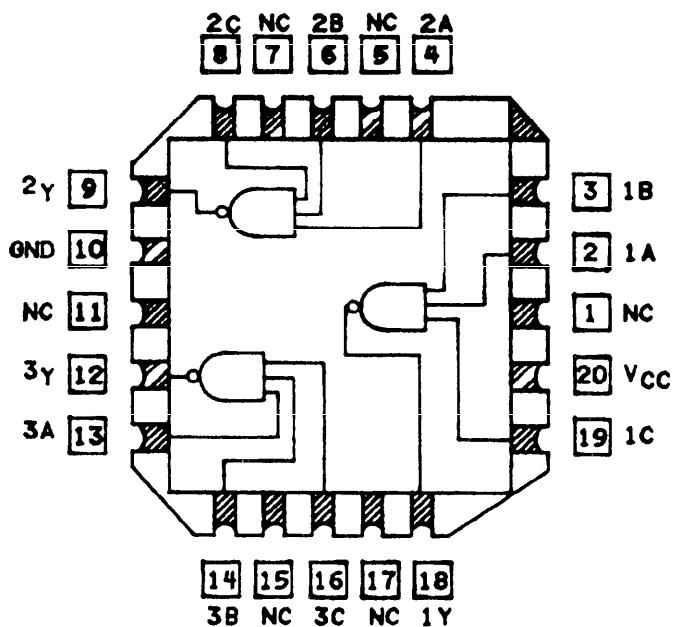


FIGURE 1. Logic diagram and terminal connections (top view).

Device type 06
Cases A, B, C, and D

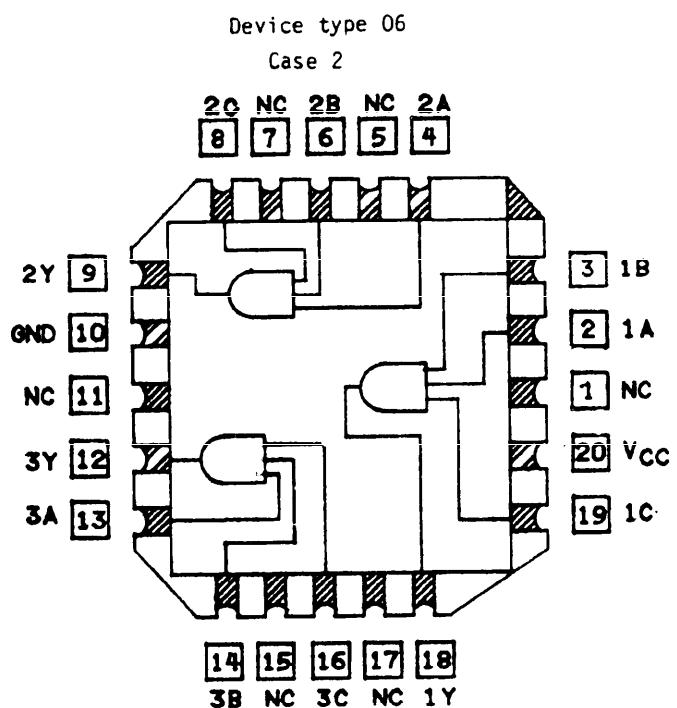
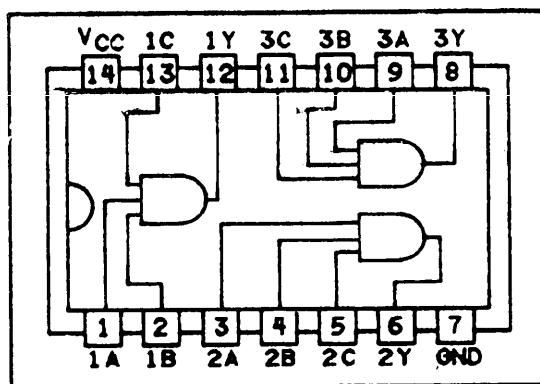


FIGURE 1. Logic diagram and terminal connections (top view)

Device type 07
Cases A, B, C, and D

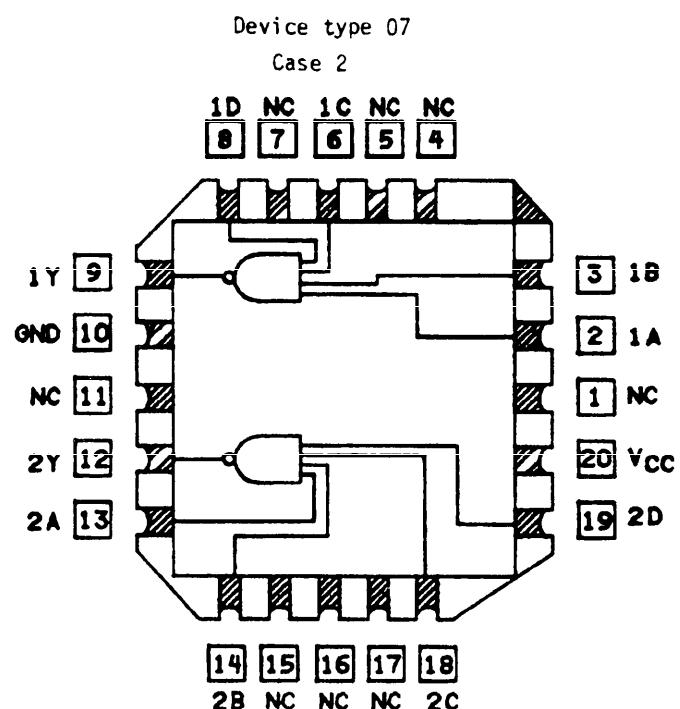
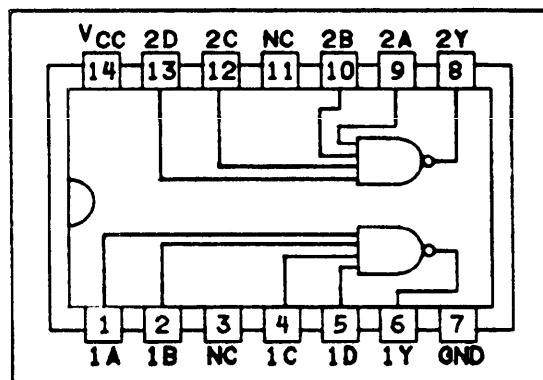
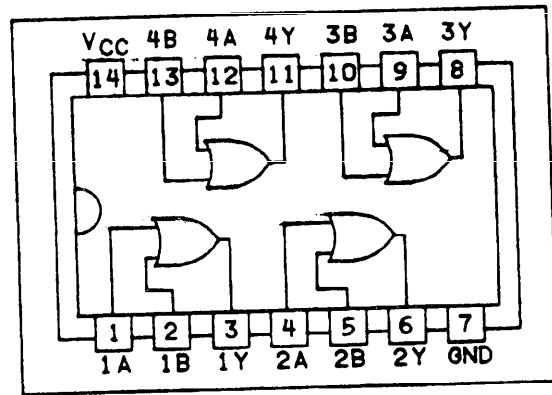


FIGURE 1. Logic diagram and terminal connections (top view).

Device type 08
Cases A, B, C, and D



Device type 08

Case 2

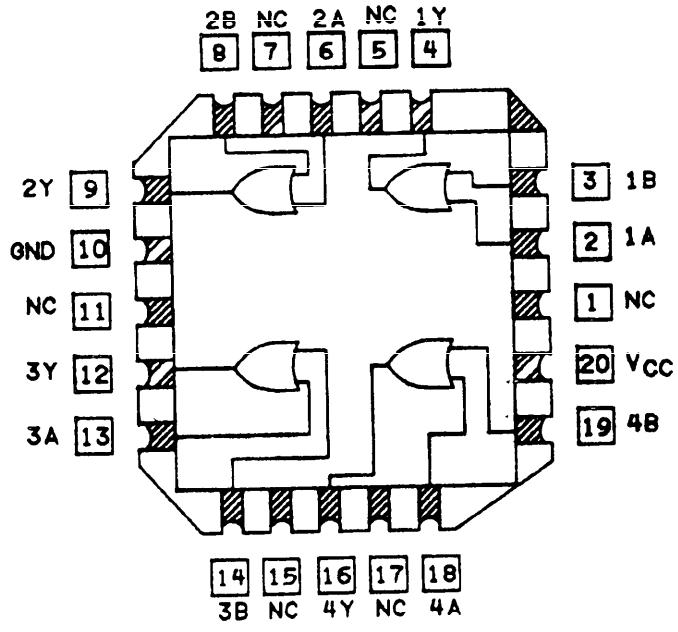
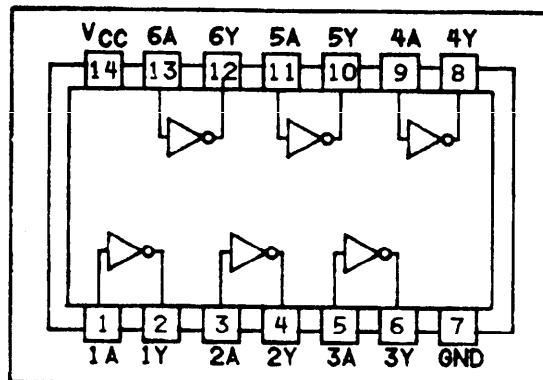


FIGURE 1. Logic diagram and terminal connections (top view).

Device type 09 and 10
Cases A, B, C, and D



Device type 09 and 10
Case 2

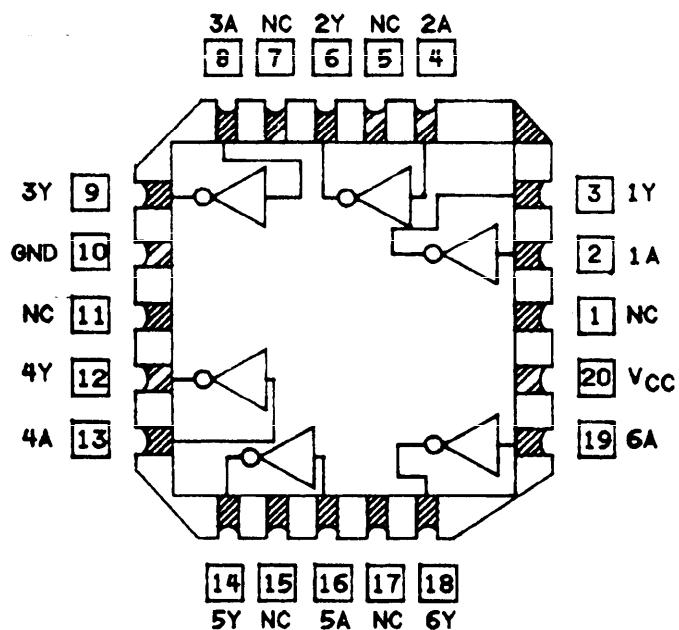
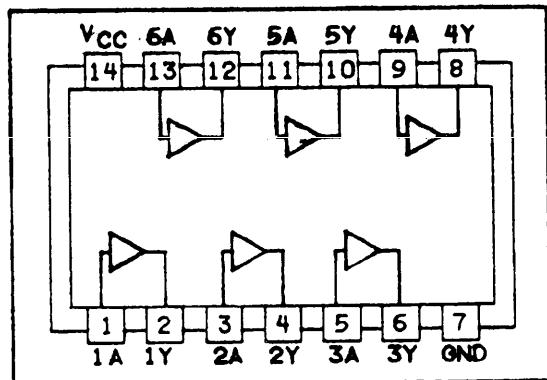


FIGURE 1. Logic diagram and terminal connections (top view).

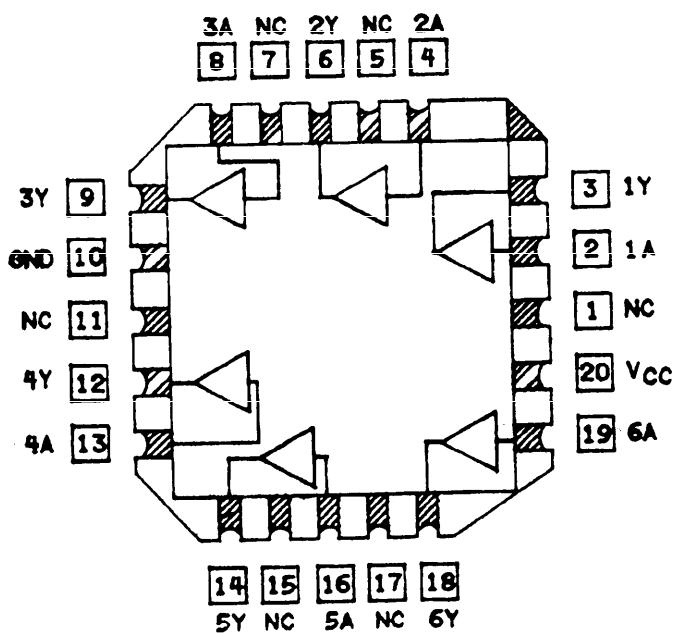
Device type 11 and 12

Cases A, B, C, and D



Device type 11 and 12

Case 2

FIGURE 1. Logic diagram and terminal connections (top view).

Device Types 01, 03

TRUTH TABLE (EACH GATE)		
INPUTS		OUTPUT
A	B	Y
L	L	H
H	L	H
L	H	H
H	H	L

$$Y = \overline{AB}$$

Device Type 02

TRUTH TABLE (EACH GATE)		
INPUTS		OUTPUT
A	B	Y
L	L	H
H	L	L
L	H	L
H	H	L

$$Y = \overline{A} + B$$

Device Type 04

TRUTH TABLE (EACH GATE)		
INPUTS		OUTPUT
A	B	Y
L	L	L
H	L	L
L	H	L
H	H	H

$$Y = AB$$

Device Type 05

TRUTH TABLE (EACH GATE)			
INPUTS		OUTPUT	
A	B	C	Y
L	L	L	H
H	L	L	H
L	H	L	F
L	L	H	H
H	H	L	H
H	L	H	H
L	H	H	H
H	H	H	L

$$Y = \overline{ABC}$$

Device Type 06

TRUTH TABLE (EACH GATE)			
INPUTS		OUTPUT	
A	B	C	Y
L	L	L	L
H	L	L	L
L	H	L	L
L	L	H	L
H	H	L	L
H	L	H	L
L	H	H	L
H	H	H	H

$$Y = ABC$$

Device Type 07

TRUTH TABLE (EACH GATE)				
INPUTS				OUTPUT
A	B	C	D	Y
L	L	L	L	H
H	L	L	L	H
L	H	L	L	H
L	L	H	L	H
H	L	L	H	H
H	H	L	H	H
L	H	H	L	H
H	L	H	H	H
L	H	H	H	H
L	L	H	H	H
H	L	H	H	H
H	H	L	H	H
L	H	H	H	L

$$Y = \overline{ABCD}$$

Device Type 08

TRUTH TABLE (EACH GATE)		
INPUTS		OUTPUT
A	B	Y
L	L	L
H	L	H
L	H	H
H	H	H

$$Y = A + B$$

Device types 09 and 10

TRUTH TABLE EACH GATE	
INPUT	OUTPUT
A	Y
L	H
H	L

$$Y = \overline{A}$$

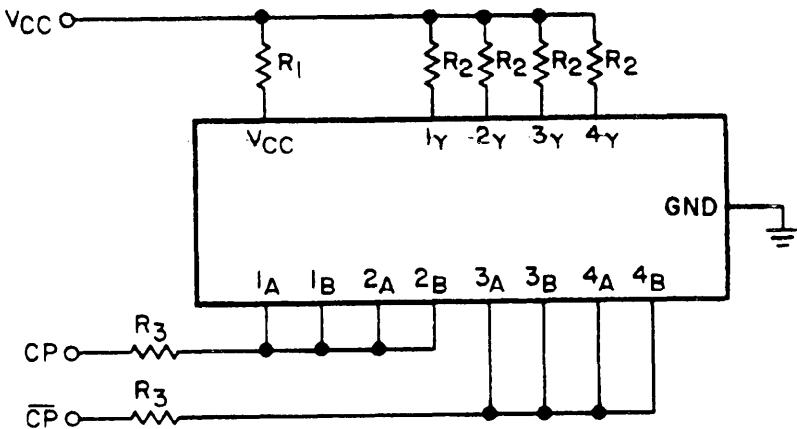
Device types 11 and 12

TRUTH TABLE EACH GATE	
INPUT	OUTPUT
A	Y
H	H
L	L

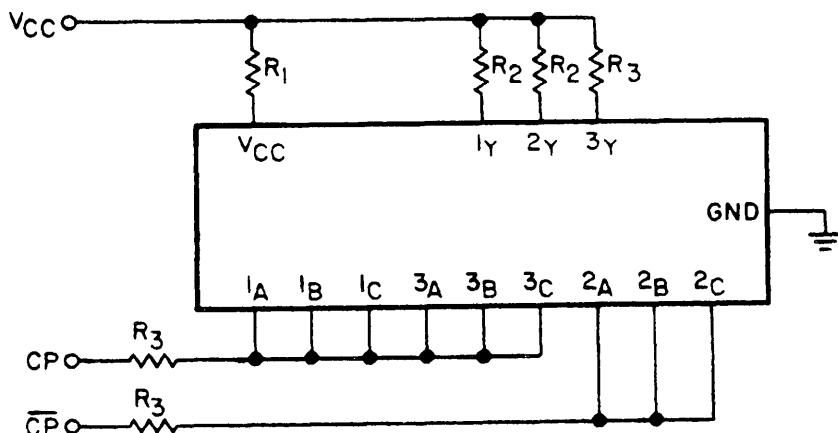
$$Y = A$$

FIGURE 2. Truth tables and logic equations.

Device Types 01, 02, 03, 04, and 08



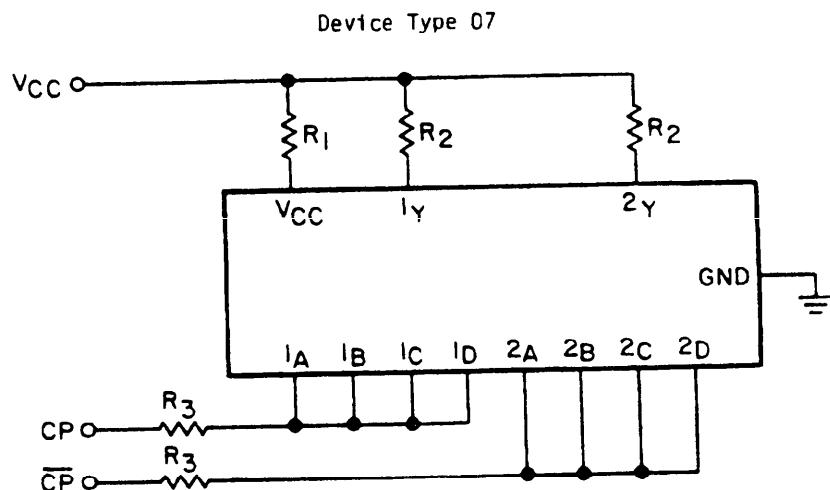
Device types 05 and 06



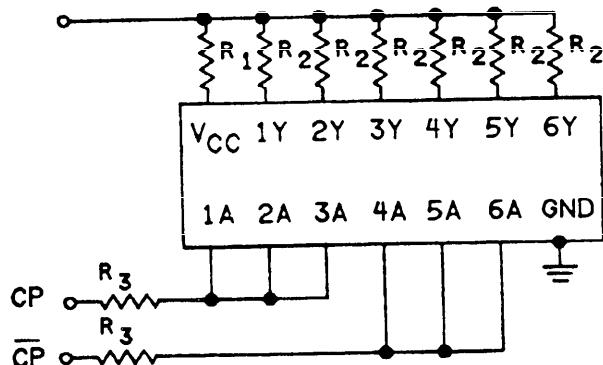
NOTES:

1. CP or \overline{CP} = 100 kHz $\pm 50\%$ square wave; duty cycle = $50 \pm 15\%$; $V_{IL} = -0.5$ V minimum to 0.8 V maximum; $V_{IH} = 2.0$ V minimum to 5.5 V maximum.
2. $R_2 = 470\Omega \pm 5\%$; $R_3 = 27\Omega$ maximum.
3. R_1 and V_{CC} shall be chosen to insure 5.0 V minimum is present at device V_{CC} terminal.

FIGURE 3. Burn-in and life test circuits.



Device types 09, 10, 11, and 12

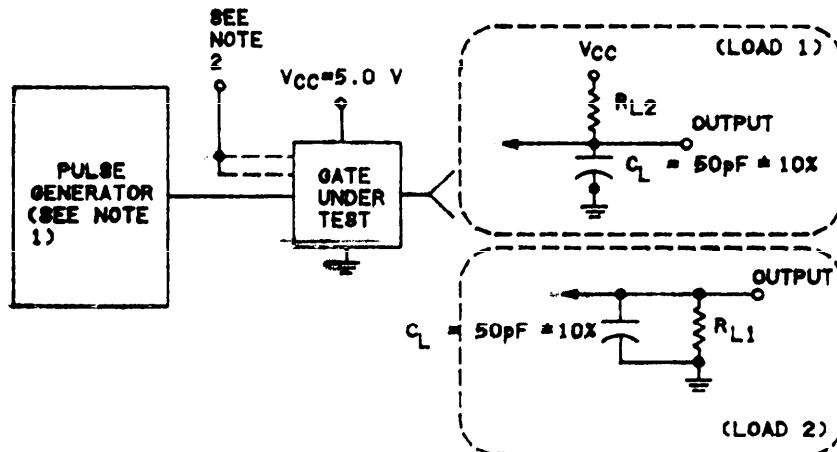
 $V_{CC} = 5.0 \text{ V MIN}$ 

NOTES:

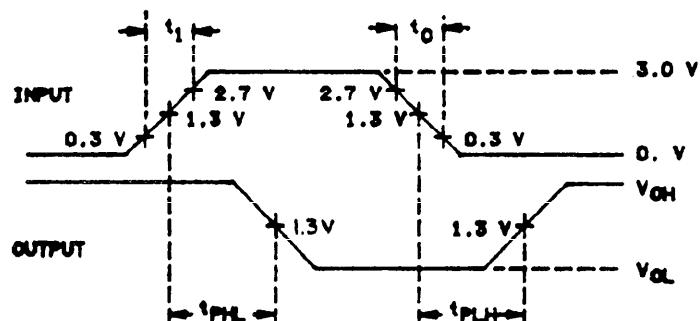
1. CP or \overline{CP} = 100 kHz $\pm 50\%$ square wave; duty cycle = $50 \pm 15\%$; $V_{IL} = -0.5 \text{ V minimum}$ to 0.8 V maximum ; $V_{IH} = 2.0 \text{ V minimum to } 5.5 \text{ V maximum}$.
2. $R_2 = 470\Omega \pm 5\%$; $R_3 = 27\Omega$ maximum.
3. R_1 and V_{CC} shall be chosen to insure 5.0 V minimum is present at device V_{CC} terminal.

FIGURE 3. Burn-in and life test circuits - Continued.

Device types 01, 02, 03, 05, 07, 09, and 10



TEST CIRCUIT



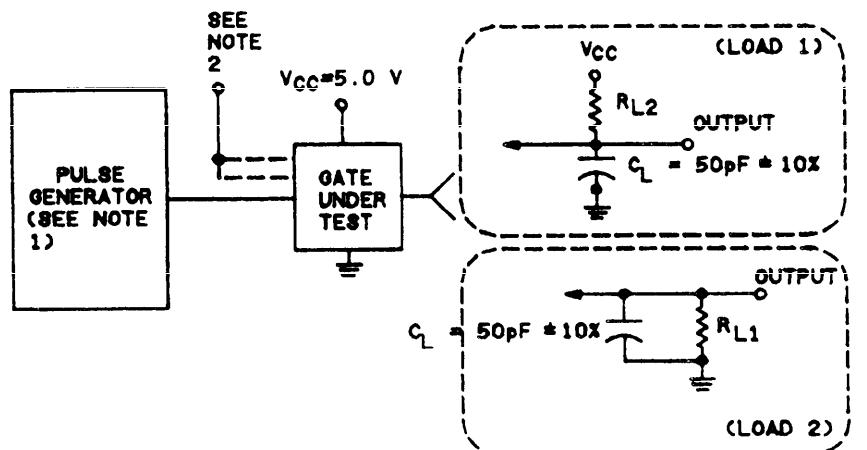
VOLTAGE WAVEFORMS

NOTES:

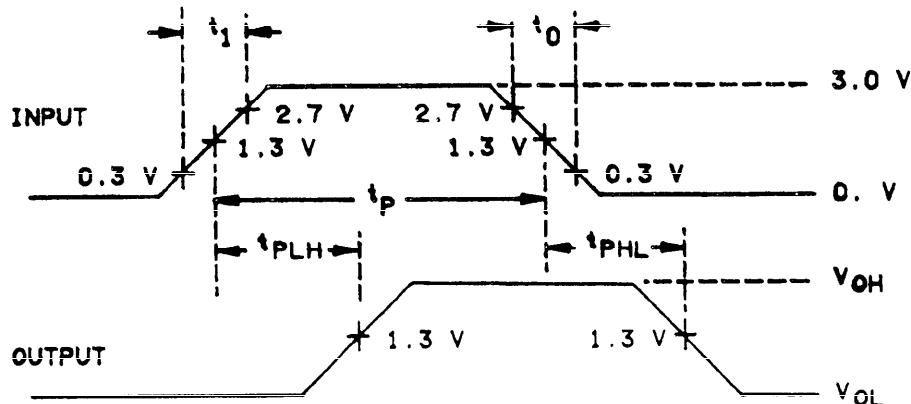
1. Input pulse characteristics: $t_1 = t_0 = 6 \pm 1.5\text{ ns}$; PRR $\leq 1\text{ MHz}$; duty cycle = 50%.
2. Inputs not under test, for device types 01, 03, 05, and 07 are 2.7 V; for device type 02 is ground.
3. $C_L = 50\text{ pF} \pm 10\%$, includes jig and probe capacitance.
4. $R_{L1} = 499\Omega \pm 1\%$ for device types 01, 02, 05, 07 and 09; $R_{L2} = 680\Omega \pm 5\%$ for device types 03 and 10.
5. Voltage measurements are made with respect to ground terminal.

FIGURE 4. Switching time test circuit and waveforms for device types 01, 02, 03, 05, 07, 09 and 10.

Device types 04, 06, 08, 11, and 12



TEST CIRCUIT



VOLTAGE WAVEFORMS

NOTES:

1. Input pulse characteristics: $t_1 = t_0 = 6 \pm 1.5\text{ ns}$; PRR $\leq 1\text{ MHz}$; duty cycle = 50%.
2. Inputs not under test, for device types 04, and 06 are 2.7 V; for device type 08 is ground.
3. $C_L = 50\text{ pF} \pm 10\%$, includes jig and probe capacitance.
4. $R_{L1} = 499\Omega \pm 1\%$ for device types 04, 06, 08, and 11; $R_{L2} = 680\Omega \pm 5\%$ for device types 12.
5. Voltage measurements are made with respect to ground terminal.

FIGURE 4. Switching time test circuit and waveforms for device types 04, 06, 08, 11, and 12.

TABLE III. Group A inspection for device type 01.

Terminal conditions (pins not designated may be high or low < 0.8 V or open).

MIL-M-38510/384 (USAF)

Subgroup	Symbol	MIL-STD-883 method	Cases	1	2	3	4	5	6	7	8	9	10	11	12	13	14	limits	
			A,B,C,D	Case 1	Case 2	Case 3	Case 4	Case 5	Case 6	Case 7	Case 8	Case 9	Case 10	Case 11	Case 12	Case 13	Case 14	Measured terminal	Min Max Unit
$T_C = +25^\circ C$	V_{OH}	3006	1	0.8 V	2.0 V	-1.0 mA											4.5 V	IV	12.4
			2	2.0 V	0.8 V	-1.0 mA	0.8 V	2.0 V	-1.0 mA								-	IV	-
			3				2.0 V	0.8 V	-1.0 mA								-	IV	-
			4														-	IV	-
		3007	5														-	IV	-
			6														-	IV	-
			7														-	IV	-
			8														-	IV	-
$T_C = -40^\circ C$	V_{OL}	3008	9	2.0 V	2.0 V	12 mA	2.0 V	2.0 V	12 mA	2.0 V	2.0 V	12 mA	2.0 V	2.0 V	12 mA	2.0 V	IV	10.4	
			10														-	IV	-
			11														-	IV	-
			12														-	IV	-
		3009	13	1.0 mA	-18 mA												0	1A	-1.5
			14														-	1A	-
			15														-	1A	-
			16														-	1A	-
$T_C = -40^\circ C$	V_{OL}	3010	17	-18 mA													-	1A	-
			18														-	1A	-
			19														-	1A	-
			20														-	1A	-
		3011	21	0.4 V	0.4 V		0.4 V	0.4 V									5.5 V	1A	2.7
			22														-	1A	-
			23														-	1A	-
			24														-	1A	-
$T_C = -40^\circ C$	V_{IH1}	3012	25	-0.4 V													-	1A	-
			26														-	1A	-
			27														-	1A	-
			28														-	1A	-
		3013	29	2.7 V	2.7 V		2.7 V	2.7 V									-	1A	-
			30														-	1A	-
			31														-	1A	-
			32														-	1A	-
$T_C = -40^\circ C$	V_{IH2}	3014	33	-3.0 V													-	1A	-
			34														-	1A	-
			35														-	1A	-
			36														-	1A	-
		3015	37	7.0 V	7.0 V		7.0 V	7.0 V									-	1A	-
			38														-	1A	-
			39														-	1A	-
			40														-	1A	-
10	3016	34/46	41	-4.0 V													-	1A	-
			42														-	1A	-
			43														-	1A	-
			44														-	1A	-

See footnotes at end of table.

TABLE III. Group A inspection for device type 01 - Continued.

terminal conditions [pins not designated may be high > 2.0 V or low < 0.8 V or open].

Subgroup	Symbol	MIL-STO 883	Cases	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Limits
			A,B,C,D	Case 1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured
T _C = +25°C	t _{PLH}	3003	51	2.7 V	2.7 V	IN	2.7 V	OUT	OUT	2.7 V	OUT	GND	OUT	2.7 V	IN	2.7 V	5.0 V	
		F19.4	52	-	-	-	-	-	-	-	-	-	-	-	-	-	1A to 1V	
			53	-	-	-	-	-	-	-	-	-	-	-	-	-	1B to 1V	
			54	-	-	-	-	-	-	-	-	-	-	-	-	-	2A to 2V	
			55	-	-	-	-	-	-	-	-	-	-	-	-	-	2B to 2V	
			56	-	-	-	-	-	-	-	-	-	-	-	-	-	3A to 3V	
			57	-	-	-	-	-	-	-	-	-	-	-	-	-	3B to 3V	
			58	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
T _C = +125°C	t _{PHL}	59	2.7 V	2.7 V	IN	2.7 V	OUT	OUT	2.7 V	IN	OUT	2.7 V	OUT	2.7 V	IN	2.7 V	5.0 V	
		60	2.7 V	2.7 V	IN	2.7 V	OUT	OUT	2.7 V	IN	OUT	2.7 V	OUT	2.7 V	IN	2.7 V	1A to 1V	
		61	-	-	-	-	-	-	-	-	-	-	-	-	-	-	1B to 1V	
		62	-	-	-	-	-	-	-	-	-	-	-	-	-	-	2A to 2V	
		63	-	-	-	-	-	-	-	-	-	-	-	-	-	-	2B to 2V	
		64	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3A to 3V	
		65	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3B to 3V	
		66	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
T _C = -55°C	t _{PLH}	Same tests, and terminal conditions as subgroup 9 except T _C = +125°C.																
T _C = +125°C t _{PHL}	Same tests, and terminal conditions as subgroup 10 except T _C = -55°C.																	

1/ Pins not referenced are N/C.

2/ I_{IL} limits in μ A as follows:

Test	A	B	C
I _{IL}	0/-100	0/-100	0/-100

3/ Method 3011 shall be used, except the output voltage shall be as specified herein, and the output current shall be operating rather than short circuit current. The output conditions have been chosen to produce a current that closely approximates one half of the true short circuit output current [0.5A].

4/ 10 min/max limit for circuits B and C shall be: -30/-110 mA.

TABLE III. Group A inspection for device type 02.
Terminal conditions (pins not designated may be high \geq 2.0 V or low \leq 0.8 V or open).

Subgroup	Symbol	Cases A,B,C,D Case 2	Test no.	V _{OH}	V _{OL}	I _{OL}	I _{OH}	V _{CC}	Measured terminal								Limits						
									1	2	3	4	5	6	7	8	9	10	11	12	13	14	
$T_c = +25^\circ C$	I _V	3006	1	-1.0 mA	0.8 V	0.8 V	-1.0 mA	0.8 V	0.8 V	0.8 V	0.8 V	0.8 V	0.8 V	0.8 V	0.8 V	0.8 V	-1.0 mA	0.8 V	0.8 V	-1.0 mA	0.4 V	2.4 V	
		-	2	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
	I _{V₀}	3007	5	12 mA	2.0 V	0.8 V	12 mA	2.0 V	0.8 V	2.0 V	0.8 V	2.0 V	0.8 V	2.0 V	0.8 V	2.0 V	12 mA	2.0 V	0.8 V	12 mA	2.0 V	0.4 V	2.4 V
		-	6	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
	I _{V_C}	13	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		14	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
	I _{I_L}	3009	21	-	0.4 V	0.4 V	-	0.4 V	0.4 V	-	0.4 V	0.4 V	-	0.4 V	0.4 V	-	-	-	-	-	-	-	
		-	22	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
	I _{I_{H1}}	3010	29	-	2.7 V	2.7 V	-	2.7 V	2.7 V	-	2.7 V	2.7 V	-	2.7 V	2.7 V	-	-	-	-	-	-	-	
		-	30	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
	I _{I_{H2}}	-	31	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		-	32	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
	I _O	3011	45	-	2.25 V	GND	GND	2.25 V	GND	GND	GND	GND	GND	GND	GND	GND	2.25 V	GND	GND	2.25 V	4 V	4 V	
		3/4	46	-	47	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		"	48	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	

See footnotes at end of table.

TABLE III. Group A Inspection for device type 02 - Continued.

Terminal conditions (pins not designated may be high > 2.0 V or low < 0.8 V or open).

Subgroup	Symbol	MIL-STD-883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Limits
1	T _{CCH}	3005	49	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	Measured terminal Min Max Unit	
T _C = +25°C	T _{CCCL}	3005	50	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V	V _{CC} 2.8 mA	
2	Same tests, terminal conditions, and limits as for subgroup 1 except T _C = +125°C and V _{IC} tests are omitted.																	
3	Same tests, terminal conditions, and limits as for subgroup 1 except T _C = -55°C and V _{IC} tests are omitted.																	
T _C = +25°C	t _{PLH}	3003 F19 4	51	OUT OUT	IN GND	IN GND	OUT OUT	IN GND	IN GND	OUT OUT	IN GND	IN GND	OUT OUT	OUT OUT	OUT OUT	OUT OUT	5.0 V 1A to 1V 2A to 2V 3A to 3V 3B to 3V 4A to 4V 4B to 4V	
		-	52	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		-	53	54	55	56	57	58									-	
	t _{PHL}	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	1A to 1V 1B to 1V 2A to 2V 2B to 2V 3A to 3V 3B to 3V 4A to 4V 4B to 4V	
		-	59	OUT OUT	IN GND	IN GND	OUT OUT	IN GND	IN GND	OUT OUT	IN GND	IN GND	OUT OUT	OUT OUT	OUT OUT	OUT OUT	-	
		-	60	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		-	61	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		-	62	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		-	63	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		-	64	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		-	65	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
		-	66	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
T _C = +125°C t _{PHL}																	2 10	
10	t _{PHL}	Same tests, and terminal conditions as subgroup 9 except T _C = +125°C.															3 10	
11	Same tests, terminal conditions, and limits as subgroup 10 except T _C = -55°C.																	

1/ Pins not referenced are V_{IC}.2/ 11L limits in μ A as follows:

Test	A	B	C
11L	0/-100	0/-100	0/-100

3/ Method 3011 shall be used, except the output voltage shall be as specified herein, and the output current shall be operating rather than short circuit current. The output conditions have been chosen to produce a current that closely approximates one half of the true short circuit output current loss.

4/ 10 min/max limit for circuits B and C shall be: -30/-110 mA.

TABLE III. Group A inspection for device type 03.

Terminal conditions (pins not designated may be high or low ≤ 0.8 V or open).

See footnotes at end of table.

TABLE III. Group A inspection for device type 03 - Continued.

terminal conditions (pins not designated may be high > 2.0 V or low < 0.8 V or open).

1/ Pins not referenced are N/C.

2/ In limits in uA as follows:

100	100	100	100	100
100	100	100	100	100
100	100	100	100	100
100	100	100	100	100
100	100	100	100	100

TABLE III. Group A Inspection for device type 04.
Terminal conditions (pins not designated may be High \geq 2.0 V or Low \leq 0.8 V or open).

Subgroup	Symbol	MIL-STD-883 method	Cases, A,B,C,D	Test no.	Measured terminal												Limits		
					1	2	3	4	5	6	7	8	9	10	11	12	13	14	Unit
$T_c = +25^\circ C$	V_{OH}	3006	1	2.0 V	-1.0 mA	2.0 V	-1.0 mA	CND	-1.0 mA	2.0 V	4.5 V	2.4 V	v dc						
		-	2	5.5 V	0.8 V	5.5 V	0.8 V	-	-	-	-	-	-	-	-	-	2V	2V	-
		-	3	5.5 V	0.8 V	5.5 V	0.8 V	-	-	-	-	-	-	-	-	-	3V	3V	-
		-	4	5.5 V	0.8 V	5.5 V	0.8 V	-	-	-	-	-	-	-	-	-	4V	4V	-
	V_{OL}	3007	5	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.4 V	0.4 V
		-	6	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.4 V	0.4 V
		-	7	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.4 V	0.4 V
		-	8	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.4 V	0.4 V
		-	9	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.4 V	0.4 V
		-	10	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.4 V	0.4 V
		-	11	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	12 mA	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.4 V	0.4 V
	V_{IC}	3008	13	-18 mA	-18 mA	-	-	-	-	-	-	-	-	-	-	-	-	1A	-1.5
		-	14	-18 mA	-18 mA	-	-	-	-	-	-	-	-	-	-	-	-	1A	-1.5
		-	15	-18 mA	-18 mA	-	-	-	-	-	-	-	-	-	-	-	-	1A	-1.5
		-	16	-18 mA	-18 mA	-	-	-	-	-	-	-	-	-	-	-	-	1A	-1.5
		-	17	-18 mA	-18 mA	-	-	-	-	-	-	-	-	-	-	-	-	1A	-1.5
		-	18	-18 mA	-18 mA	-	-	-	-	-	-	-	-	-	-	-	-	1A	-1.5
		-	19	-18 mA	-18 mA	-	-	-	-	-	-	-	-	-	-	-	-	1A	-1.5
		-	20	-18 mA	-18 mA	-	-	-	-	-	-	-	-	-	-	-	-	1A	-1.5
	I_{IL}	3009	21	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	5.5 V	2 / 1A
		-	22	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	5.5 V	2 / 1A
		-	23	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	5.5 V	2 / 1A
		-	24	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	5.5 V	2 / 1A
		-	25	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	5.5 V	2 / 1A
		-	26	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	5.5 V	2 / 1A
		-	27	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	5.5 V	2 / 1A
		-	28	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	5.5 V	2 / 1A
	I_{IH1}	3010	29	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	20 ..
		-	30	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	20 ..
		-	31	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	20 ..
		-	32	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	20 ..
		-	33	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	20 ..
		-	34	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	20 ..
		-	35	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	20 ..
		-	36	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	20 ..
		-	37	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	20 ..
	I_{IH2}	3011	38	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	100 ..
		-	39	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	100 ..
		-	40	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	100 ..
		-	41	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	100 ..
		-	42	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	100 ..
		-	43	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	100 ..
		-	44	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	100 ..
		-	45	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	100 ..
		-	46	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	100 ..
		-	47	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	100 ..
		-	48	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	100 ..

See footnotes at end of table.

TABLE III. Group A inspection for device type 04 - Continued.

Terminal conditions (pins not designated may be high ≥ 2.0 V or low ≤ 0.8 V or open).

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11. **What are the differences between NCC and NCG?**

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Test	111
Count	111
A	111
B	111
C	111
D	111
E	111
F	111
G	111
H	111
I	111
J	111
K	111
L	111
M	111
N	111
O	111
P	111
Q	111
R	111
S	111
T	111
U	111
V	111
W	111
X	111
Y	111
Z	111

3/ Method 3011 shall be used, except the output voltage shall be as specified herein, and the output current shall be operating rather than short circuit current. The output conditions have been chosen to produce a current that closely approximates one half of the true short circuit output current [05-]

11. Is minimum limit for articles B and C shall be: -30/-110 mA.

TABLE III. Group A inspection for device type 35.
 Terminal conditions [pins not designated may be high > 2.0 V or low ≤ 0.8 V or open].

Subgroup	Symbol	MIL-STD-883 method	Cases A,B,C,D		Cases 1,2		Cases 3,4		Cases 5,6		Cases 7,8		Cases 9,10		Cases 11,12		Cases 13,14		Limits	
			Test no.	V _{OH}	V _{OL}	V _{IL}	V _{IL}	V _{OL}	V _{OL}	V _{IL}	V _{IL}	V _{OL}	V _{OL}	V _{IL}	V _{IL}	V _{OL}	V _{OL}	V _{DC}		
T _C = +25°C			3006	1 0.8 V	2.0 V	0.8 V	-	2.0 V	0.8 V	2.0 V	0.8 V	1.0 mA	-1.0 mA	-1.0 mA	-1.0 mA	2.0 V	4.5 V	1 V	2.4 V	
			-	2 2.0 V	-	3 0.8 V	-	2.0 V	0.8 V	2.0 V	0.8 V	-1.0 mA	-1.0 mA	-1.0 mA	-1.0 mA	2.0 V	-	1 V	-	
			-	4 -	-	5 -	-	6 -	8 -	9 -	-	-	-	-	-	-	-	-	-	
			-	7 -	-	8 -	-	9 -	-	-	-	-	-	-	-	-	-	-	-	
V _{OL}	3007		10 -	2.0 V	-	-	-	-	12 mA	2.0 V	-	1 V	0.4 V							
	-		11 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	2 V	-	-
V _{IC}			13 -	-	-	-18 mA	-	-	-	-	-	-	-	-	-	-	-	-	3 V	-
			14 -	-	-	-	-18 mA	-	-	-	-	-	-	-	-	-	-	-	-	-
			15 -	-	-	-	-	-18 mA	-	-	-	-	-	-	-	-	-	-	1.5 V	-
			16 -	-	-	-	-	-	-18 mA	-	-	-	-	-	-	-	-	-	1.5 V	-
			17 -	-	-	-	-	-	-18 mA	-	-	-	-	-	-	-	-	-	1.5 V	-
			18 -	-	-	-	-	-	-18 mA	-	-	-	-	-	-	-	-	-	1.5 V	-
			19 -	-	-	-	-	-	-	-18 mA	-	-	-	-	-	-	-	-	1.5 V	-
			20 -	-	-	-	-	-	-	-18 mA	-	-	-	-	-	-	-	-	1.5 V	-
			21 -	-	-	-	-	-	-	-	-18 mA	-	-	-	-	-	-	-	1.5 V	-
V _{IL}	3009		22 -	0.4 V	0.4 V	-	-	-	-	-	-	-	-	-	-	-	5.5 V	1 A	2 V	2 V
	-		23 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	1 B	1 C	-
			24 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	2 A	2 B	-
			25 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	2 C	2 D	-
			26 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3 A	3 B	-
			27 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3 C	3 D	-
			28 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
			29 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
			30 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
V _{IM1}	3010		31 -	2.7 V	2.7 V	-	-	-	-	-	-	-	-	-	-	-	-	1 A	2 B	-
	-		32 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	1 C	2 A	-
			33 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	2 C	2 D	-
			34 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3 A	3 B	-
			35 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3 C	3 D	-
			36 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
			37 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
			38 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
			39 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
V _{IM2}			40 -	7.0 V	7.0 V	-	-	-	-	-	-	-	-	-	-	-	-	1 A	1 B	1 C
			41 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	2 A	2 B	2 C
			42 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3 A	3 B	3 C
			43 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
			44 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
			45 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
			46 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
			47 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
			48 -	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-

See footnotes at end of table.

TABLE III. Group A inspection for device type 05 - Continued.

Terminal conditions (pins not designated may be high > 2.0 V or low < 0.8 V or open).

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22 / The limits in μA as follows:

001./0	001./0	001./0	111
2	8	4	1321
312112			

Method 2011 shall be used, except the output voltage shall be as specified herein, and the output current shall be operating rather than short circuit current. The output conditions have been chosen to produce a current that closely approximates one half of the true short circuit output current [5].

// Invertor limit for circuits B and C shall be: -30/-110 mA.

Terminal conditions (pins not designated may be high > 2.0 V or low <

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See footnotes at end of table.

TABLE III. Group A inspection for device type 06 - Continued.

Terminal conditions (pins not designated may be high or low) $< 0.8 \text{ V}$ or open).

[same facts terminal conditions and limits as for subgroup I except $T_r = +125^{\circ}\text{C}$ and Vic tests are omitted.

Same tests and initial conditions as subproblem 9 except $T_c = +125^\circ\text{C}$.

125 CTPHL

Bins not referenced are N/C.

22/ The limits in mas follows:

001-10	001-10	001-10	11111

Method 1011 shall be used, except the output voltage shall be a specified herein, and the output current shall be operating rather than short circuit current. The output conditions have been chosen to produce a current that closely approximates one half of the true short circuit output current loss.

10 min/max limit for circuits B and C shall be: -30/-110 mA.

TABLE III. Group A Inspection for device type 07.
Terminal conditions (pins not designated may be high > 2.0 V or low < 0.8 V or open).

Terminal conditions (pins not designated may be high > 2.0 V or low < 0.8 V or open).

Subgroup	Symbol	Cases A,B,C,D MIL-STD-883 method	Measured terminal										Limits		
			1	2	3	4	5	6	7	8	9	10	11	12	13
$T_C = +25^\circ\text{C}$	V_{OH}	3006	1	0.8 V	2.0 V	2.0 V	-1.0 mA	0.8 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V
		-	2	2.0 V	2.0 V	2.0 V	-1.0 mA	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V
		-	3	2.0 V	2.0 V	2.0 V	-1.0 mA	0.8 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V
		-	4	2.0 V	2.0 V	2.0 V	-1.0 mA	0.8 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V	2.0 V
		-	5	-	-	-	-	-	-	-	-	-	-	-	-
		-	6	-	-	-	-	-	-	-	-	-	-	-	-
		-	7	-	-	-	-	-	-	-	-	-	-	-	-
		-	8	-	-	-	-	-	-	-	-	-	-	-	-
V_{OL}	3007	9	2.0 V	2.0 V	2.0 V	2.0 V	12 mA	-	2.0 V	2.0 V	2.0 V				
	3007	10	-	-	-	-	-	-	-	-	-	-	-	-	-
V_{IC}		11	-	-18 mA	-	-	-	-	-	-	-	-	-	-	-
		12	-	-18 mA	-	-	-	-	-	-	-	-	-	-	-
		13	-	-	-18 mA	-	-	-	-	-	-	-	-	-	-
		14	-	-	-	-18 mA	-	-	-	-	-	-	-	-	-
		15	-	-	-	-	-18 mA	-	-	-	-	-	-	-	-
		16	-	-	-	-	-	-	-	-	-	-	-	-	-
		17	-	-	-	-	-	-18 mA	-	-	-	-	-	-	-
		18	-	-	-	-	-	-	-	-	-	-	-	-	-
I_{IL}	3009	19	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V
		20	-	-	-	-	-	-	-	-	-	-	-	-	-
		21	-	-	-	-	-	-	-	-	-	-	-	-	-
		22	-	-	-	-	-	-	-	-	-	-	-	-	-
		23	-	-	-	-	-	-	-	-	-	-	-	-	-
		24	-	-	-	-	-	-	-	-	-	-	-	-	-
		25	-	-	-	-	-	-	-	-	-	-	-	-	-
		26	-	-	-	-	-	-	-	-	-	-	-	-	-
I_{TH1}	3010	27	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V
		28	-	-	-	-	-	-	-	-	-	-	-	-	-
		29	-	-	-	-	-	-	-	-	-	-	-	-	-
		30	-	-	-	-	-	-	-	-	-	-	-	-	-
		31	-	-	-	-	-	-	-	-	-	-	-	-	-
		32	-	-	-	-	-	-	-	-	-	-	-	-	-
		33	-	-	-	-	-	-	-	-	-	-	-	-	-
		34	-	-	-	-	-	-	-	-	-	-	-	-	-
I_{TH2}		35	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V	7.0 V
		36	-	-	-	-	-	-	-	-	-	-	-	-	-
		37	-	-	-	-	-	-	-	-	-	-	-	-	-
		38	-	-	-	-	-	-	-	-	-	-	-	-	-
		39	-	-	-	-	-	-	-	-	-	-	-	-	-
		40	-	-	-	-	-	-	-	-	-	-	-	-	-
		41	-	-	-	-	-	-	-	-	-	-	-	-	-
		42	-	-	-	-	-	-	-	-	-	-	-	-	-
I_{CCH}	3005	45	GND	GND	GND	GND	2.25 V	2.25 V	GND	GND	GND	GND	GND	1V	-30 V
		46	GND	GND	GND	GND	-	-	GND	GND	GND	GND	GND	-2V	-30 V

See footnotes at end of table.

TABLE III. Group A inspection for device type 07 - Continue.

Terminal conditions (pins not designated may be high > 2.0 V or low < 0.8 V or open):

and 1961; 22 for sulphuric] event $T_c = 112^\circ\text{C}$ and Yir tests are omitted.

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$\Delta H_f^\circ + 125^\circ\text{C}$ (ppm)

REVIEW ARTICLE

Same tests, terminal conditions, and limits as Sung's paper.

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Pins not referenced are N/C.

17. Entries in "A" as follows:

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test

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Method 3011 shall be used, except the output voltage shall be specified as short circuit operating rather than short circuit.

The output conditions have been chosen to produce a current that can be used as a reference current for the current loop.

closely approximates one half of the total energy.

10 min/max limit for circuits B and C shall be: -30/-110 m.s.

TABLE III. Group A inspection for device type 08.

terminal conditions (pins not designated may be high > 2.0 V or low < 0.8 V or open).

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See footnotes at end of table.

TABLE III. Group A inspection for device type 08 - Continued.

Subgroup	Symbol	Cases A, B, C, D MIL-STO 883	Method Test no.	Terminal conditions (pins not designated may be high > 2.0 V or low < 0.8 V or open).										Measured terminal limits	Unit				
				1	2	3	4	5	6	7	8	9	10	11	12				
$T_C = +25^\circ\text{C}$	I _{CCH}	Case 1/ 2	3	4	6	8	9	10	12	13	14	16	18	19	20	Y _{CC}	mA		
	I _{CCL}	3005	1A	1B	1Y	2A	2B	2Y	GND	3A	3B	4A	4B	48	48	Y _{CC}	mA		
2	Same tests, terminal conditions, and limits as for subgroup 1 except $T_C = +125^\circ\text{C}$ and Y _{IC} tests are omitted.															5.0 mA			
	3 Same tests, terminal conditions, and limits as for subgroup 1 except $T_C = -55^\circ\text{C}$ and Y _{IC} tests are omitted.															5.0 V			
$T_C = +25^\circ\text{C}$	I _{PHL}	Fig. 4	3003	51	IN	GND	OUT	GND	"	"	"	"	"	"	"	1A to 1Y	2	10 ms	
	I _{PHL}	-	52	53	54	55	56	57	58	GND	IN	OUT	OUT	OUT	OUT	1B to 1Y	-	-	
9	I _{PHL}	-	59	IN	GND	OUT	OUT	IN	GND	IN	GND	OUT	IN	GND	IN	1B to 2Y	-	-	
	I _{PHL}	-	60	61	62	63	64	65	66	GND	IN	OUT	OUT	IN	GND	1B to 2Y	-	-	
10	I _{PHL}	-	67	68	69	70	71	72	73	74	75	76	77	78	79	1A to 3Y	-	-	
	I _{PHL}	-	78	79	80	81	82	83	84	85	86	87	88	89	89	1A to 4Y	-	-	
11	I _{PHL}	-	90	91	92	93	94	95	96	97	98	99	100	101	102	1A to 4Y	-	-	
	I _{PHL}	-	103	104	105	106	107	108	109	110	111	112	113	114	115	1A to 4Y	-	-	
12	I _{PHL}	-	116	117	118	119	120	121	122	123	124	125	126	127	128	1B to 3Y	-	-	
	I _{PHL}	-	129	130	131	132	133	134	135	136	137	138	139	140	141	1B to 4Y	-	-	
13	I _{PHL}	-	142	143	144	145	146	147	148	149	150	151	152	153	154	1B to 4Y	-	-	
	I _{PHL}	-	155	156	157	158	159	160	161	162	163	164	165	166	167	1B to 4Y	-	-	
14	I _{PHL}	-	168	169	170	171	172	173	174	175	176	177	178	179	180	1B to 4Y	-	-	
	I _{PHL}	-	181	182	183	184	185	186	187	188	189	190	191	192	193	1B to 4Y	-	-	
15	I _{PHL}	-	194	195	196	197	198	199	200	201	202	203	204	205	206	207	1B to 4Y	-	-
	I _{PHL}	-	208	209	210	211	212	213	214	215	216	217	218	219	220	221	1B to 4Y	-	-
16	I _{PHL}	-	222	223	224	225	226	227	228	229	230	231	232	233	234	235	1B to 4Y	-	-
	I _{PHL}	-	236	237	238	239	240	241	242	243	244	245	246	247	248	249	1B to 4Y	-	-
17	I _{PHL}	-	250	251	252	253	254	255	256	257	258	259	260	261	262	263	1B to 4Y	-	-
	I _{PHL}	-	264	265	266	267	268	269	270	271	272	273	274	275	276	277	1B to 4Y	-	-
18	I _{PHL}	-	278	279	280	281	282	283	284	285	286	287	288	289	290	291	1B to 4Y	-	-
	I _{PHL}	-	292	293	294	295	296	297	298	299	300	301	302	303	304	305	1B to 4Y	-	-
19	I _{PHL}	-	306	307	308	309	310	311	312	313	314	315	316	317	318	319	1B to 4Y	-	-
	I _{PHL}	-	320	321	322	323	324	325	326	327	328	329	330	331	332	333	1B to 4Y	-	-
20	I _{PHL}	-	334	335	336	337	338	339	340	341	342	343	344	345	346	347	1B to 4Y	-	-
	I _{PHL}	-	348	349	350	351	352	353	354	355	356	357	358	359	360	361	1B to 4Y	-	-
21	I _{PHL}	-	362	363	364	365	366	367	368	369	370	371	372	373	374	375	1B to 4Y	-	-
	I _{PHL}	-	376	377	378	379	380	381	382	383	384	385	386	387	388	389	1B to 4Y	-	-
22	I _{PHL}	-	390	391	392	393	394	395	396	397	398	399	400	401	402	403	1B to 4Y	-	-
	I _{PHL}	-	404	405	406	407	408	409	410	411	412	413	414	415	416	417	1B to 4Y	-	-
23	I _{PHL}	-	418	419	420	421	422	423	424	425	426	427	428	429	430	431	1B to 4Y	-	-
	I _{PHL}	-	432	433	434	435	436	437	438	439	440	441	442	443	444	445	1B to 4Y	-	-
24	I _{PHL}	-	446	447	448	449	450	451	452	453	454	455	456	457	458	459	1B to 4Y	-	-
	I _{PHL}	-	460	461	462	463	464	465	466	467	468	469	470	471	472	473	1B to 4Y	-	-
25	I _{PHL}	-	474	475	476	477	478	479	480	481	482	483	484	485	486	487	1B to 4Y	-	-
	I _{PHL}	-	488	489	490	491	492	493	494	495	496	497	498	499	500	501	1B to 4Y	-	-
26	I _{PHL}	-	502	503	504	505	506	507	508	509	510	511	512	513	514	515	1B to 4Y	-	-
	I _{PHL}	-	516	517	518	519	520	521	522	523	524	525	526	527	528	529	1B to 4Y	-	-
27	I _{PHL}	-	530	531	532	533	534	535	536	537	538	539	540	541	542	543	1B to 4Y	-	-
	I _{PHL}	-	544	545	546	547	548	549	550	551	552	553	554	555	556	557	1B to 4Y	-	-
28	I _{PHL}	-	558	559	560	561	562	563	564	565	566	567	568	569	570	571	1B to 4Y	-	-
	I _{PHL}	-	572	573	574	575	576	577	578	579	580	581	582	583	584	585	1B to 4Y	-	-
29	I _{PHL}	-	586	587	588	589	590	591	592	593	594	595	596	597	598	599	1B to 4Y	-	-
	I _{PHL}	-	599	600	601	602	603	604	605	606	607	608	609	610	611	612	1B to 4Y	-	-
30	I _{PHL}	-	613	614	615	616	617	618	619	620	621	622	623	624	625	626	1B to 4Y	-	-
	I _{PHL}	-	627	628	629	630	631	632	633	634	635	636	637	638	639	640	1B to 4Y	-	-
31	I _{PHL}	-	641	642	643	644	645	646	647	648	649	650	651	652	653	654	1B to 4Y	-	-
	I _{PHL}	-	655	656	657	658	659	660	661	662	663	664	665	666	667	668	1B to 4Y	-	-
32	I _{PHL}	-	671	672	673	674	675	676	677	678	679	680	681	682	683	684	1B to 4Y	-	-
	I _{PHL}	-	685	686	687	688	689	690	691	692	693	694	695	696	697	698	1B to 4Y	-	-
33	I _{PHL}	-	699	700	701	702	703	704	705	706	707	708	709	710	711	712	1B to 4Y	-	-
	I _{PHL}	-	713	714	715	716	717	718	719	720	721	722	723	724	725	726	1B to 4Y	-	-
34	I _{PHL}	-	727	728	729	730	731	732	733	734	735	736	737	738	739	740	1B to 4Y	-	-
	I _{PHL}	-	741	742	743	744	745	746	747	748	749	750	751	752	753	754	1B to 4Y	-	-
35	I _{PHL}	-	755	756	757	758	759	760	761	762	763	764	765	766	767	768	1B to 4Y	-	-
	I _{PHL}	-	769	770	771	772	773	774	775	776	777	778	779	780	781	782	1B to 4Y	-	-
36	I _{PHL}	-	785	786	787	788	789	790	791	792	793	794	795	796	797	798	1B to 4Y	-	-
	I _{PHL}	-	799	800	801	802	803	804	805	806	807	808	809	810	811	812	1B to 4Y	-	-
37	I _{PHL}	-	813	814	815	816	817	818	819	820	821	822	823	824	825	826	1B to 4Y	-	-
	I _{PHL}	-	827	828	829	830	831	832	833	834	835	836	837	838	839	840	1B to 4Y	-	-
38																			

TABLE III. Group A inspection for device type 09, 10.

terminal condition: pins not designated may be high > 2.0 V or low < 0.8 V or open

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See footnotes at end of table.

TABLE III. Group A Inspection for device type 09, 10 - Continued.

Terminal conditions (pins not designated may be high ≥ 2.0 V or low ≤ 0.8 V or open).																			
		Cases		1	2	3	4	5	6	7	8	9	10	11	12	13	14	Limits	
Subgroup	Symbol: MIL-S10-883	A, B, C, D	Case 1	7	3	4	6	8	9	10	12	13	14	16	18	19	20	Measured	
Method	Test no.	Test no.	Case 2	7X	7Y	7X	2Y	3X	3Y	GND	4V	4A	5Y	5A	6Y	6A	VCC	Terminal	
	Type	Type		09	10												Min Max	Limit	
$T_C = +25^\circ C$	I _{CCH}	3006	I _C	43	37	GND	5.5 V	V _{CC}	3 mA										
	I _{CCL}	3005	I _C	44	38	4.5 V	5.5 V	V _{CC}	12 mA										
2 Same tests, terminal conditions, and limits as for subgroup 1 except $T_C = +125^\circ C$ and YIC tests are omitted.																			
3 Same tests, terminal conditions, and limits as for subgroup 1 except $T_C = -55^\circ C$ and YIC tests are omitted.																			
$T_C = +25^\circ C$	I _{PHH}	3003	I _P	45	39	IN	OUT	IN	5.0 V	IA to LY	7/ 7/ ns								
		Fig. 4		46	40												12A to 2Y		
				47	41												1A to 3Y		
				48	42												4A to 4Y		
				49	43												5A to 5Y		
				50	44												6A to 6Y		
$T_C = +125^\circ C$	I _{PHL}			51	45	IN	OUT	IN	1A to 1Y	8/ 8/									
				52	46												12A to 2Y		
				53	47												1A to 3Y		
				54	48												4A to 4Y		
				55	49												5A to 5Y		
				56	50												6A to 6Y		
$T_C = -55^\circ C$	I _{PLH}																		
10 Same tests and terminal conditions as subgroup 9 except $T_C = 125^\circ C$.																		9/ 9/	
11 Same tests, terminal conditions, and limits as subgroup 10 except $T_C = -55^\circ C$.																		10/ 10/	
1/ Pins not referenced are N/C.																			
2/ 09 only.																			
3/ All limits in μA as follows:																			
4/ Method 3011 shall be used, except the output voltage shall be as specified herein, and the output current shall be operating rather than short circuit current. The output conditions have been chosen to produce a current that closely approximates one half of the true short circuit output current I_{OS} .																			
5/ 10 min/max limit for circuits 8 and C shall be: -30/-110 μA .																			
6/ 10 only.																			
7/ for device type 09:																			
8/ for device type 10:																			
9/ for device type 09:																			
10/ for device type 09:																			
11/ for device type 10:																			
12/ for device type 10:																			

TABLE III. Group A Inspection for device type 11, 12.

Terminal conditions (pins not designated may be high \geq 2.0 V or low \leq 0.8 V or open).

Subgroup	Symbol	MIL-STO- 1883	A,B,C,D method	Test no. Case 1/ 2	Cases												Units														
					1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	Measured terminal	Min	Max	Unit			
																										V DC					
	I_{Q1}	3006	1	1	0.8 V	12 mA	0.8 V	12 mA	0.8 V	12 mA																					
	V_{IC}	13	7	18 mA	14	8	15	9	16	10	17	11	18	12	19	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27	28
	I_{IH1}	3009	19	13	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V	0.4 V																			
	I_{IH2}	3010	25	19	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V	2.7 V																			
	I_{IG}	3011	37	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	2.25 V	5.5 V	
	I_{IG}	38	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	5.5 V	5.0 V	

See footnotes at end of table.

TABLE 111. Group A Inspection for device type 11, 12 - Continued.

Subgroup	Symbol	Cases A,B,C,D Case 17 2	Terminal conditions (pins not designated may be high ≥ 2.0 V or low ≤ 0.8 V or open).												Limits	
			Test no.	Type	1A	1Y	2X	2Y	3A	3Y	GND	4A	4Y	5A	6A	
T _C = +25°C	ICCH	3005	11 12 43 37	4.5 V	4.5 V						GMC	4.5 V	4.5 V	4.5 V	5.5 V	V _{CC} 6 ns
T _C = +25°C	ICCL	3005	44 18	GND	GND						GMC	GND	GND	GND	5.5 V	V _{CC} 14 ns
2 Same tests, terminal conditions, and limits as for subgroup 1 except T _C = +125°C and VIC tests are omitted.																
3 Same tests, terminal conditions, and limits as for subgroup 1 except T _C = -55°C and VIC tests are omitted.																
T _C = +25°C	t _{plH}	9 3003 Fig. 4	45 46 47 48 49 50	39 40 41 42 43 44	1N	OUT	1N	OUT	1N	OUT	GND	*	*	*	5.0 V	IA to 1Y 2A to 2Y 3A to 3Y 4A to 4Y 5A to 5Y 6A to 6Y
T _C = +25°C	t _{plH}	51 52 53 54 55 56	45 46 47 48 49 50	1N	OUT	1N	OUT	1N	OUT	IN	OUT	IN	OUT	IN	*	IA to 1Y 2A to 2Y 3A to 3Y 4A to 4Y 5A to 5Y 6A to 6Y
10 t _{plH} Same tests and terminal conditions as subgroup 9 except T _C = +125°C.																
T _C = +125°C t _{plH}																
T _C = -55°C																
11 Same tests, terminal conditions, and limits as subgroup 10 except T _C = -55°C.																
T _C = -55°C																

1/ Pins not referenced are N/C.
 2/ 11 only.
 3/ 11L limits in μ A as follows:

Circuit				
Test	A	B	C	
11L	10/-100	10/-100	10/-100	

- 4/ Method 3011 shall be used, except the output voltage shall be as specified herein, and the output current shall be operating rather than short circuit current. The output conditions have been chosen to produce a current that closely approximates one half of the true short circuit output current I_{OS}.
 5/ 10 min/max limit for circuits B and C shall be: -30/-110 μ A.
 6/ 12 only.
- | Test | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 | 13 | 14 | 15 | 16 |
|------|--|---|----|----|----|----|----|----|----|----|----|----|----|----|----|----|
| 7/ | for device type 11:
for device type 12: | 5 | 30 | ns |
| 8/ | for device type 11:
for device type 12: | 1 | 8 | 12 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 |
| 9/ | for device type 11:
for device type 12: | 1 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 | 10 |
| 10/ | for device type 11:
for device type 12: | 1 | 35 | 35 | 35 | 35 | 35 | 35 | 35 | 35 | 35 | 35 | 35 | 35 | 35 | 35 |
| 11/ | for device type 11:
for device type 12: | 2 | 14 | 14 | 14 | 14 | 14 | 14 | 14 | 14 | 14 | 14 | 14 | 14 | 14 | 14 |

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Notes. The notes specified in MIL-M-38510 are applicable to this specification.

6.2 Intended use. Microcircuits conforming to this specification are intended for original equipment design applications and logistic support of existing equipment.

6.3 Ordering data. The acquisition document should specify the following:

- a. Complete part number (see 1.2).
- b. Requirements for delivery of one copy of the quality conformance inspection data pertinent to the device inspection lot to be supplied with each shipment by the device manufacturer, if applicable.
- c. Requirements for certificate of compliance, if applicable.
- d. Requirements for notification of change of product or process to the contracting activity in addition to notification to the qualifying activity, if applicable.
- e. Requirements for failure analysis (including required test condition of method 5003 of MIL-STD-883), corrective action and reporting of results, if applicable.
- f. Requirements for product assurance options.
- g. Requirements for special carriers, lead lengths, or lead forming, if applicable. These requirements shall not affect the part number. Unless otherwise specified, these requirements shall not apply to direct purchase by or direct shipment to the Government.
- h. Requirements for "JAN" marking.

6.4 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-M-38510, MIL-STD-1331, and as follows:

GND	- - - - -	Ground zero voltage potential.
V _{IN}	- - - - -	Voltage level at an input terminal.
V _{IC}	- - - - -	Input clamp voltage.
I _{IN}	- - - - -	Current flowing into an input terminal.

6.5 Logistic support. Lead materials and finishes (see 3.3) are interchangeable. Unless otherwise specified, microcircuits acquired for Government logistic support will be acquired to device class B (see 1.2.2), lead material and finish C (see 3.3). Longer length leads and lead forming shall not affect the part number.

6.6 Substitutability. The cross-reference information below is presented for the convenience of users. Microcircuits covered by this specification will functionally replace the listed generic-industry type. Generic-industry microcircuit types may not have equivalent operational performance characteristics across military temperature ranges or reliability factors equivalent to MIL-M-38510 device types and may have slight physical variations in relation to case size. The presence of this information shall not be deemed as permitting substitution of generic-industry types for MIL-M-38510 types or as a waiver of any of the provisions of MIL-M-38510.

<u>Military device type</u>	<u>Generic-industry type</u>
01	54ALS1000/54ALS37
02	54ALS1002/54ALS28
03	54ALS1003/54ALS38
04	54ALS1008
05	54ALS1010
06	54ALS1011
07	54ALS1020/54ALS40
08	54ALS1032
09	54ALS1004
10	54ALS1005
11	54ALS1034
12	54ALS1035

6.7 Manufacturers' designators. Manufacturers' circuits which form a part of this specification are designated with an "X" as shown in table IV herein.

TABLE IV. Manufacturers' designations.

Device type	Circuit		
	A Texas Instruments	B Motorola	C National
01	X		
02	X		
03	X		
04	X		
05	X		
06	X		
07	X		
08	X		
09	X		
10	X		
11	X		
12	X		

Custodians:
Air Force - 17

Preparing activity:
Air Force - 17

Review activities:
Air Force - 11, 19, 85, 99
DLA - ES

(Project 5962-F636)

Agent:
DLA - ES

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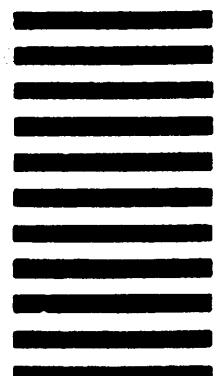
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STANDARDIZATION DOCUMENT IMPROVEMENT PROPOSAL

(See Instructions - Reverse Side)

1. DOCUMENT NUMBER M3851U/384(USAF)	2. DOCUMENT TITLE Microcircuits, Digital, Advanced Low Power Schottky TTL, AND, OR, NAND, AND NOR Gates Monolithic Silicon
3. NAME OF SUBMITTING ORGANIZATION	
4. ADDRESS (Street, City, State, ZIP Code)	
5. PROBLEM AREAS	
<p>a. Paragraph Number and Wording:</p> <p>b. Recommended Wording:</p> <p>c. Reason/Rationale for Recommendation:</p> 	
6. REMARKS	
7. NAME OF SUBMITTER (Last, First, MI) - Optional	
8. MAILING ADDRESS (Street, City, State, ZIP Code) - Optional	
9. WORK TELEPHONE NUMBER (Include Area Code) - Optional	
10. DATE OF SUBMISSION (YYMMDD)	